

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Patent Application of:

Shunpei YAMAZAKI et al.

Serial No. 09/832,867

Filed: April 12, 2001

For: LIGHT EMITTING DEVICE

COMPRISING THIN FILM

TRANSISTOR WITH DISTINCT

POSITION OF GATE ELECTRODE

AND IMPURITY REGIONS

) Group Art Unit: 2822

) Examiner: M. Lewis

) CERTIFICATE OF MAILING

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Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 37 C.F.R. 1.97-1.99, Applicant submits herewith a Form PTO-1449 listing information known to Applicant and requests that this information be made of record in the above identified application. Copies are submitted herewith in accordance with 37 C.F.R. 1.98(a).

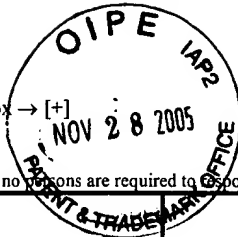
This Information Disclosure Statement is being submitted with an RCE. Therefore, no fee is required.

Respectfully submitted,

Eric J. Robinson
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Reg. No. 38,285

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PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

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				Application Number	09/832,867
				Filing Date	April 12, 2001
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2822
				Examiner Name	M. Lewis
				Attorney Docket Number	0756-2294
Sheet	1	of	2		

U.S. PATENT DOCUMENTS						
Examiner Initials [*]	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² <i>(if known)</i>			
		2001/0055841		Yamazaki et al.	12/27/2001	
		2003/0057419		Murakami et al.	03/27/2003	
		2005/0040400		Yamazaki et al.	02/24/2005	
		5,412,493		Kunii et al.	05/02/1995	
		5,414,547		Matsuo et al.	05/09/1995	
		5,441,618		Matsuda et al.	08/15/1995	
		5,499,123		Mikoshiba	03/12/1996	
		5,659,375		Yamashita et al.	08/19/1997	
		5,677,207		Ha	10/14/1997	
		5,708,485		Sato et al.	01/13/1998	
		5,708,486		Miyawaki et al.	01/13/1998	
		5,726,720		Watanabe et al.	03/10/1998	
		5,733,420		Matsuda et al.	03/31/1998	
		5,815,226		Yamazaki et al.	09/29/1998	
		5,818,550		Kadota et al.	10/06/1998	
		6,002,462		Sato et al.	12/14/1999	
		6,031,512		Kadota et al.	02/29/2000	
		6,078,060		Shibuya et al.	06/20/2000	
		6,087,679		Yamazaki et al.	07/11/2000	
		6,104,461		Zhang et al.	08/15/2000	

FOREIGN PATENT DOCUMENTS							
Examiner Initials [*]	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office ³	Number ⁴	Kind Code ⁵ <i>(if known)</i>			
		JP	08-160464			06/21/1996	Abst.
		JP	08-328000			12/13/1996	Abst.
		JP	10-154814			06/09/1998	Abst.
		JP	2000-315798			11/14/2000	Abst.

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		R. SHIMOKAWA, et al., <i>Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement</i> , Japanese Journal of Applied Physics, May 1, 1988, Volume 27, No. 5, Pages 751-758.	
Examiner Signature		Date Considered	

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Sheet	2	of	2	Attorney Docket Number	0756-2294

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Sheet 1 of 3

Complete if Known

Application Number 09/832,867
Filing Date April 12, 2001
First Named Inventor Shunpei YAMAZAKI, et al.
Group Art Unit 2822
Examiner Name Monica Lewis
Attorney Docket Number 0756-2294

FOREIGN PATENT DOCUMENTS

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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
		JP	04-369271		Takeda et al.	12/22/92		FULL
		JP	05-102483		Ueda	04/23/93		FULL
		JP	06-037314		Tsuchimoto	02/10/94		AB
		JP	07-202210		Taniguchi	08/04/95		AB
		JP	08-078329		Otani	03/22/96		AB
		JP	08-051207		Sato	02/20/96		AB
		JP	08-110530		Koyama et al.	04/30/96		AB
		JP	10-135469		Yamazaki et al.	05/22/98		AB
		JP	10-144929		Shibuya et al.	05/29/98		AB
		EP	0 451 968		Coxon	10/16/91		ENG
		JP	10-247735		Takano et al.	09/14/98		AB
		EP	0 803 911		Adan et al.	10/29/97		ENG
		JP	10-135468		Yamazaki et al.	05/22/98		AB

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		Tanaka, et al., "Ultrafast Operation of V _{th} -Adjusted p ⁺ -n ⁺ Double-Gate SOI MOSFET'S," IEEE Electron Device Letters, Vol. 15 (Oct., 1994), No. 10, pp. 386-388.	ENG
		Inui et al., "Thresholdless Antiferroelectricity in Liquid Crystals and its Application to Displays," J. Mater. Chem., 1996, 6(4), pp. 671-673.	ENG
		Takada, et al., PROCEEDINGS OF 46 TH SPRING MEETINGS OF THE SOCIETY FOR APPLIED PHYSICS OF JAPAN, 28P-V-8, page 1316.	NONE
		Hwang et al., "Novel Polysilicon/TiN Stacked-Gate Structure for Fully-Depleted SOI/CMOS," IEDM '92, pp. 345-348.	ENG
		Yoshihara, EKISHO, Vol. 3, No. 3, pp. 190-194.	NONE
		Furue et al., "P-78: Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCD Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability," SID '98 DIGEST, pp. 782-785.	ENG
		Hatano et al., "A Novel Self-Aligned Gate-Overlapped LDD Poly-Si TFT with High Reliability and Performance," IEDM '97, pp. 523-526.	ENG

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